

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 218298US0CONT	SERIAL NO. New Application
		APPLICANT Shigeru AIHARA, et al.	
		FILING DATE	GROUP 1745

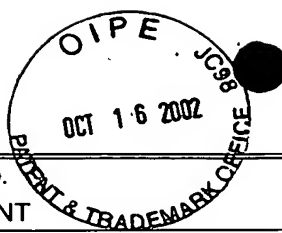
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>AS</i>	AA	4,220,693	09/02/80	R.B. DI PALMA, et al			
<i>AS</i>	AB	5,981,107	11/09/99	HAMANO, et al.			
<i>AS</i>	AC	6,120,940	09/2000	POEHLER, et al			
<i>AS</i>	AD	6,232,014-B1	05/2001	SHIOTA, et al			
<i>AS</i>	AE	6,235,066-B1	05/2001	INUZUKA, et al			
<i>AS</i>	AF	6,136,471	10/2000	YOSHIDA, et al			
<i>AS</i>	AG	6,124,061	09/2000	HAMANO, et al			
<i>AS</i>	AH	6,051,342	04/2000	HAMANO, et al			
<i>AS</i>	AI	6,024,773	02/2000	INUZUKA, et al			
<i>AS</i>	AJ	5,741,609	04/1998	CHEN, et al			
<i>AS</i>	AK	5,512,389	04/1996	DASGUPTA, et al			
<i>AS</i>	AL	5,498,489	03/1996	DASGUPTA, et al			
	AM						
	AN						

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
11 12 13 14 15	AO	62-8471	01/16/87	JAPAN (w/ English abstract)		X
	AP	55-41689	03/24/80	JAPAN (English Abstract only, Corr. U.S. 4,220,693)		X
	AQ	9-293518	11/11/97	JAPAN (English Abstract only)		X
	AR	6-168737	06/14/94	JAPAN (with English Abstract)		X
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)			
	AW		
	AX		
	AY		
	AZ		

Examiner <i>Shirley Liang Foster</i>	<input type="checkbox"/> Additional References sheet(s) attached
Date Considered <i>6/30/03</i>	

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



#4

SHEET 1 OF 1

Form PTO 1449
(Modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.
218298US0CONT

SERIAL NO.
10/057,913

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Shigeru AIHARA, et al.

FILING DATE
January 29, 2002

GROUP
1745

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

RECEIVED
OCT 17 2002
TC 1700

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
10	AO	49-12931	03/28/74	JAPAN		X
10	AP	51-11138	01/29/76	JAPAN		X
10	AQ	WO 97/08763	03/06/97	WIPO (with English Abstract)		X
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW		
	AX		
	AY		
	AZ		

☐ Additional References sheet(s) attached

Examiner

Sunny Isay-Lester

Date Considered 6/30/03

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.